



## **ARFTG – 2<sup>nd</sup> Nonlinear Measurements Workshop**

**December 4<sup>th</sup> 2003, The Monarch Hotel, Washington D.C., USA**

### **Schedule**

**1:00 – 1:10 Introduction**

Dr. Jan Verspecht, Agilent Technologies, Hingene, Belgium

**1:10 – 2:00 Applications of the Non-linear Scattering Functions for the Non-linear CAD of Microwave Circuits**

Prof. Dr. Giorgio Leuzzi, Universita dell' Aquila, L' Aquila, Italy

**2:00 – 2:50 Accurate Extraction of Measurement-Based Behavioral Models for RF Power Amplifiers**

Prof. Dr. J. Stevenson Kenney, Georgia Institute of Technology, Atlanta, Georgia, USA

**2:50 – 3:10 Coffee, tea (and hopefully cookie) break**

**3:10 – 4:00 Large-Signal Time Domain Characterization of Microwave Transistors under RF Pulsed Conditions**

Dr. Jean-Pierre Teyssier, IRCOM, Limoges, France

**4:00 – 4:50 Comb-Generator Characterization with Calibrated Oscilloscopes**

Dr. Dylan Williams, National Institute of Standards and Technology, Boulder, Colorado, USA